## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10556482	AJAY ET AL.
Examiner	Art Unit
FELIX E SUAREZ	2857

## **SEARCHED**

Class	Subclass	Date	Examiner
702	14, 36, 59, 182, 183, 186, 189.	2/14/2008	FS
73	40	2/14/2008	FS
381	159	2/14/2008	FS
340	630	2/14/2008	FS
Above	UPDATED	12/19/2008	FS
Above	UPDATED	01/14/2010	FS
Above	UPDATED	09/21/2010	FS
Above	UPDATED	05/16/2011	FS
Above	UPDATED	10/20/2011	FS

## **SEARCH NOTES**

Search Notes	Date	Examiner
Search Text EAST	2/14/2008	FS
Class/subclass. 73/40, 40.05. Measuring and testing: leakage using	2/14/2008	FS
acoustic detector. Pri. Ex. Frank R. AU 2856.		
Class 702 Data processing: measurement, calibrating and testing. Pri. Ex.	2/14/2008	FS
Wachsman H. AU 2857. More search.		
SPE Ramos-Feliciano. Reviewed.	2/14/2008	FS
Search Text EAST	12/19/2008	FS
SPE Ramos-Feliciano. Reviewed.	12/19/2009	FS
Search Text EAST	01/14/2010	FS
Interview with Applicant representative and Primary Examiner AU 2857	01/15/2010	FS
Wachsman.		
SPE AU 2857 Ramos-Feliciano. Reviewed	01/22/2010	FS
Class/subclass. 340/628. Communications: Electrical; cCondition	09/21/2010	FS
responsive indicating system: Specific condition; fluent material; particle		
suspension in fluid; smoke. Ex. Bugg G. AU 2612.		
Search Text EAST	09/21/2010	FS
Primary Examiner AU 2857 Charioui M. Suggested consider 101 to claims	09/29/2010	FS
41-43, and prior art for the ultrasonic limitation to the amendement.		
Interview with Primary Examiner AU 2857 Wachsman.	01/12/2011	FS
Interview with SPE AU 2857 Ramos-Feliciano.	01/19/2011	FS
SPE AU 2857 Schechter A. Some claims have 112 2nd paragraph issues.	05/16/2011	FS
Search Text EAST	05/16/2011	FS
Primary Examiner AU 2857 Nghiem M. Reviewed	05/16/2011	FS
Search Text EAST	10/20/2011	FS

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SEARCH NOTES		
Search Notes	Date	Examiner
SPE AU 2857 Dunn D. No proper dependent claims rejection under 112 fouth paragraph is appropriate.	10/21/2011	FS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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